


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/604,289	CHEN ET AL.	
	Examiner	Art Unit	
	TUAN A. PHAM	2618	

SEARCHED			
Class	Subclass	Date	Examiner
455	575.1	8/16/2006	PHAM
	575.3		
	575.4		
	575.6	8/16/2006	PHAM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR